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AUTOMOTIVE GRADE

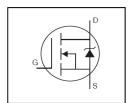
AUIRF3315S

Features

- Advanced Planar Technology
- Low On-Resistance
- Dynamic dV/dT Rating
- 175°C Operating Temperature
- Fast Switching

Description

- Fully Avalanche Rated
- Repetitive Avalanche Allowed up to Timax
- Lead-Free, RoHS Compliant
- Automotive Qualified *



	HEXEE	Power MOSFET
V _{DSS}		150V
R _{DS(on)} max.		82m Ω
I _D		21A



G	D	S
Gate	Drain	Source

Specifically designed for Automotive applications, this cellular design of

HEXFET® Power MOSFETs utilizes the latest processing techniques to achieve low on-resistance per silicon area. This benefit combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in Automotive and a wide variety of other applications.

Rose part number Bookege Type		Standard Pack		Orderable Part Number
Base part number	Package Type	Form Quantity		Orderable Part Number
AUIRF3315S	D ² -Pak	Tube	50	AUIRF3315S
AUIRESS 155	рРак	Tape and Reel Left	800	AUIRF3315STRL

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	21	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	15	Α
I _{DM}	Pulsed Drain Current ①	84	
P _D @T _A = 25°C	Maximum Power Dissipation	3.8	14/
P _D @T _C = 25°C	Maximum Power Dissipation	94	W
	Linear Derating Factor	0.63	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) ②	350	mJ
I _{AR}	Avalanche Current ①	12	Α
E _{AR}	Repetitive Avalanche Energy ®	9.4	mJ
dv/dt	Peak Diode Recovery ③	2.5	V/ns
T _J	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case®		1.6	°CAM
$R_{ heta JA}$	Junction-to-Ambient (PCB Mount, steady state) ©		40	°C/W

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^{*}Qualification standards can be found at www.infineon.com



Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	150			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.187		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance			82	$m\Omega$	$V_{GS} = 10V, I_D = 12A \oplus$
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
ı	Drain-to-Source Leakage Current	_		25	uА	$V_{DS} = 150V, V_{GS} = 0V$
I _{DSS}	Diam-to-Source Leakage Current			250	μΑ	$V_{DS} = 120V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			100	- Δ	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage			-100	nA	V _{GS} = -20V

Dynamic Electrical Characteristics @ $T_J = 25$ °C (unless otherwise specified)

	Total Cata Ohanna		٥٢		L - 40A
Q_g	Total Gate Charge	 	95		I _D = 12A
Q_{gs}	Gate-to-Source Charge	 	11	nC	$V_{DS} = 120V$
Q_gd	Gate-to-Drain Charge	 	47		V _{GS} = 10V4
$t_{d(on)}$	Turn-On Delay Time	 9.6			$V_{DD} = 75V$
t_r	Rise Time	 32		no	I _D = 12A
$t_{d(off)}$	Turn-Off Delay Time	 49		ns	$R_G = 5.1\Omega$,
t_f	Fall Time	 38			$R_D = 5.9\Omega$, $\textcircled{4}$
L_D	Internal Drain Inductance	 4.5			Between lead, 6mm (0.25in.)
L _S	Internal Source Inductance	 7.5			from package and center of die contact
C_{iss}	Input Capacitance	 1300			$V_{GS} = 0V$
Coss	Output Capacitance	 300		рF	$V_{DS} = 25V$
C _{rss}	Reverse Transfer Capacitance	 160			f = 1.0MHz, See Fig.5

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
I _S	Continuous Source Current (Body Diode)			21	_	MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ①			84		integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 12A, V_{GS} = 0V $ ④
t _{rr}	Reverse Recovery Time		174	260	ns	$T_J = 25^{\circ}C$, $I_F = 12A$
Q_{rr}	Reverse Recovery Charge		1.2	1.7	μC	di/dt = 100A/µs ④
t_{on}	Forward Turn-On Time	Intrinsi	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)			

Notes:

- $\, \oplus \,$ Repetitive rating; pulse width limited by max. junction temperature. (See fig.11)
- \odot Limited by T_{Jmax}, starting T_J = 25°C, L = 4.9mH, R_G = 25 Ω , I_{AS} = 12A. (See fig.12)
- $\label{eq:loss_def} \text{ } \text{ } I_{SD} \leq 12A, \text{ } \text{di/dt} \leq 140A/\mu\text{s}, \text{ } V_{DD} \leq V_{(BR)DSS}, \text{ } T_J \leq 175^{\circ}\text{C}.$
- 4 Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$.
- S When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994

© R_{θ} is measured at T_J of approximately 90°C

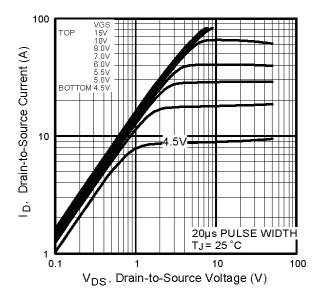


Fig. 1 Typical Output Characteristics

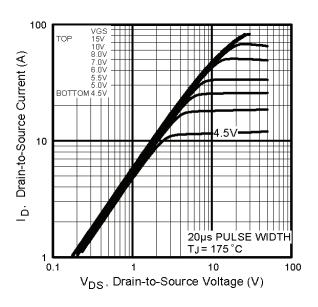


Fig. 2 Typical Output Characteristics

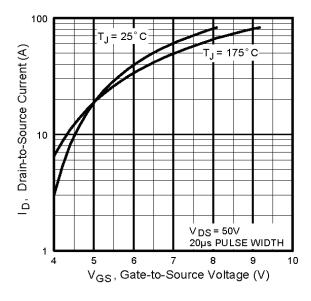


Fig. 3 Typical Transfer Characteristics

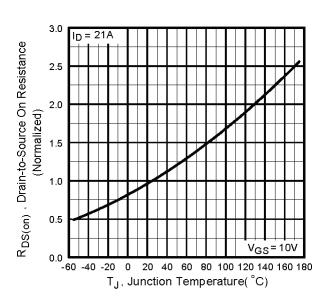


Fig. 4 Normalized On-Resistance vs. Temperature



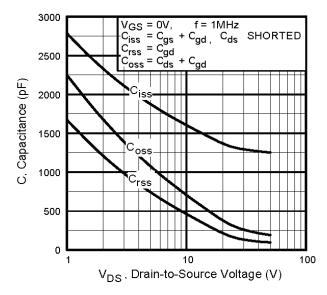


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

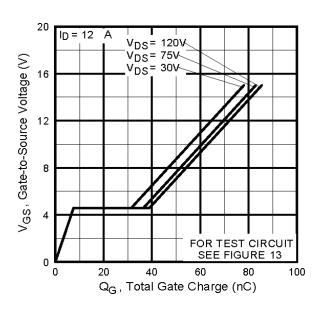


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

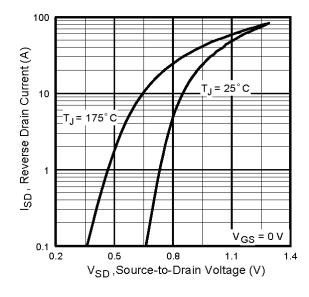


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

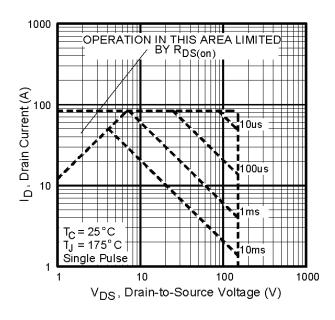


Fig 8. Maximum Safe Operating Area

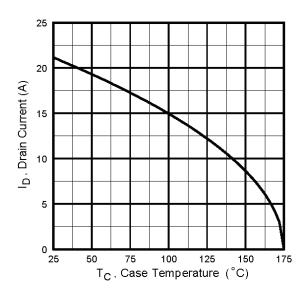


Fig 9. Maximum Drain Current vs.
Case Temperature

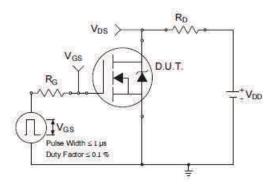


Fig 10a. Switching Time Test Circuit

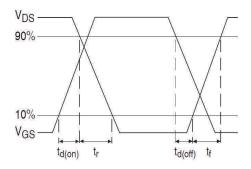


Fig 10b. Switching Time Waveforms

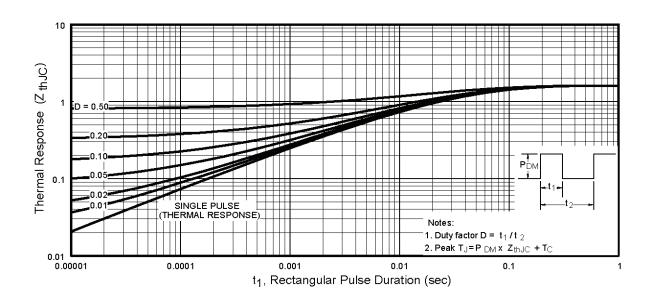


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



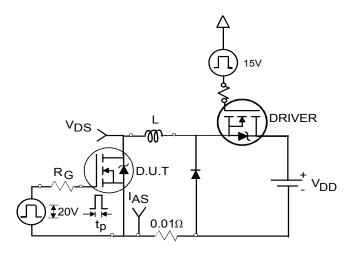


Fig 12a. Unclamped Inductive Test Circuit

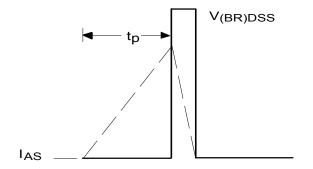


Fig 12b. Unclamped Inductive Waveforms

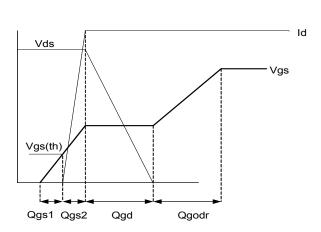


Fig 13a. Gate Charge Waveform

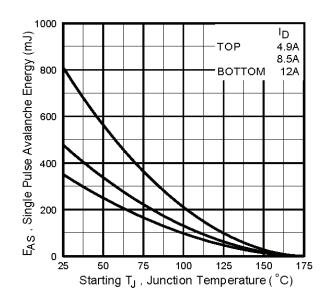


Fig 12c. Maximum Avalanche Energy vs. Drain Current

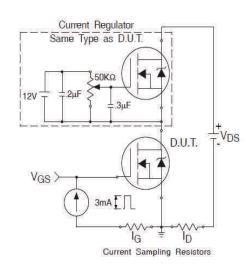
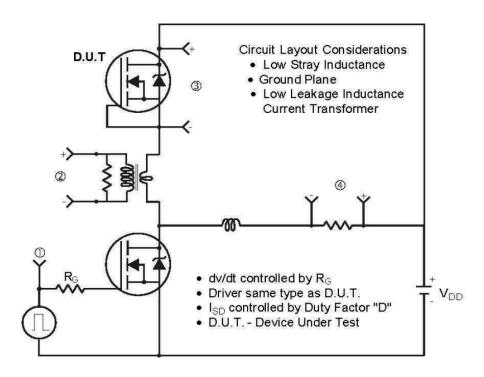


Fig 13b. Gate Charge Test Circuit



Peak Diode Recovery dv/dt Test Circuit



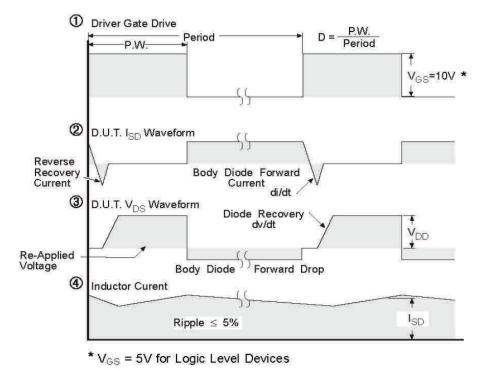
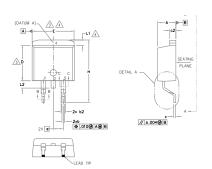
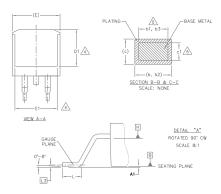


Fig 14. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs



D²Pak (TO-263AB) Package Outline (Dimensions are shown in millimeters (inches))





- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61, 63 AND c1 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H. 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

S		N			
M B	MILLIM	METERS INCHES			O T E S
O L	MIN.	MAX.	MIN.	MAX.	E S
А	4.06	4.83	.160	.190	
A1	0.00	0.254	.000	.010	
Ь	0.51	0.99	.020	.039	
ь1	0.51	0.89	.020	.035	5
b2	1.14	1.78	.045	.070	
ь3	1,14	1.73	.045	.068	5
С	0.38	0.74	.015	.029	
с1	0.38	0.58	.015	.023	5
с2	1.14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	_	.270	_	4
E	9.65	10.67	.380	.420	3,4
E1	6.22	_	.245	_	4
е	2.54	BSC	.100	BSC	
Н	14.61	15.88	.575	.625	
L	1.78	2.79	.070	.110	
L1	_	1.68	_	.066	4
L2	_	1.78	_	.070	
L3	0.25	BSC	.010	BSC	

LEAD ASSIGNMENTS

DIODES

1.— ANODE (TWO DIE) / OPEN (ONE DIE) 2, 4.— CATHODE 3.— ANODE

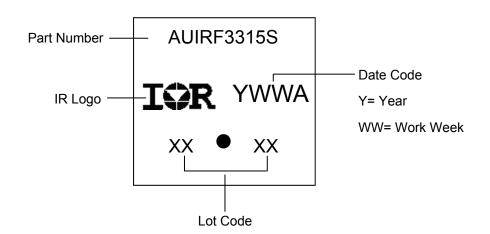
HEXFET

IGBTs, CoPACK

1.- GATE 2, 4.- DRAIN 3.- SOURCE

1.- GATE 2, 4.- COLLECTOR 3.- EMITTER

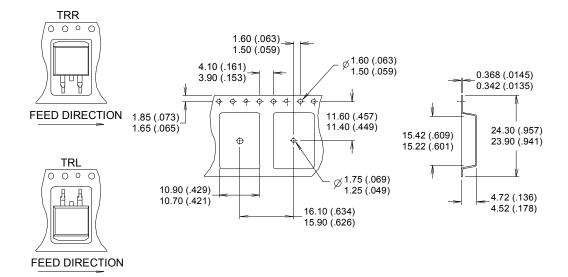
D²Pak (TO-263AB) Part Marking Information

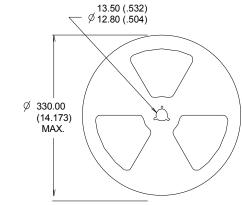


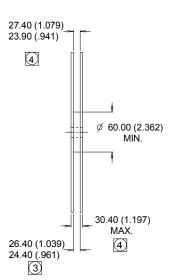
Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



D²Pak (TO-263AB) Tape & Reel Information (Dimensions are shown in millimeters (inches))







NOTES:

- 1. COMFORMS TO EIA-418.
- CONTROLLING DIMENSION: MILLIMETER.
- 3 DIMENSION MEASURED @ HUB.
- INCLUDES FLANGE DISTORTION @ OUTER EDGE.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification Information

Quaiiiiout	ion iniormation							
			Automotive					
			(per AEC-Q101)					
Qualificat	ion Level	Comments: Th	is part number(s) passed Automotive qualification. Infineon's					
		Industrial and Consumer qualification level is granted by extension of the hig						
		Automotive level.						
Moisture	Sensitivity Level	D ² -Pak MSL1						
			Class M4 (+/- 600V) [†]					
	Machine Model	AEC-Q101-002						
ECD	Human Dady Madal	Class H1C (+/- 2000V) [†]						
ESD	Human Body Model	AEC-Q101-001						
Charged Davise Medal		Class C5 (+/- 2000V) [†]						
	Charged Device Model	AEC-Q101-005						
RoHS Cor	mpliant	Yes						

[†] Highest passing voltage.

Revision History

Date	Comments
11/13/2015	 Updated datasheet with corporate template Corrected ordering table on page 1. Corrected typo in test condition current from "43A" to "12A" for VSD and trr/Qrr on page 2.

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